

L Number	Hits	Search Text	DB	Time stamp
1	3791	716/\$.ccls.	USPAT	2003/03/27 07:14
2	296	LSI same inspection	USPAT	2003/03/27 07:14
3	73	LSI same inspection same (defect or particle)	USPAT	2003/03/27 07:15
4	6	LSI same inspection same (defect or particle) and probabilit\$3	USPAT	2003/03/27 07:22
5	12055	ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/27 07:24
-	4	ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in. and hitachi\$.as.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/27 07:24
6	12024	ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in. and hitachi\$4.as.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/27 07:25
7	12016	ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in. and hitachi\$4.as. and lsi and inspection	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/27 07:25
8	5	(ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and lsi and inspection	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/27 07:28
9	42	(ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and inspection	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/27 07:28
10	37	((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and inspection) not ((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and lsi and inspection)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/27 07:28
11	433675	((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and inspection) not ((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and lsi and inspection)) and defect or failure	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/27 07:28
12	29	((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and inspection) not ((ono-m\$.in. or iwata-h\$.in. or kirino-k\$.in.) and hitachi\$4.as. and lsi and inspection)) and (defect or failure)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/27 07:47
-	548	((716/19) or (716/21)).CCLS.	USPAT	2003/03/26 14:32
-	435	(716/2).CCLS.	USPAT	2003/03/26 14:32
-	620	(716/4).CCLS.	USPAT	2003/03/26 14:33
-	985	inspect\$3 same pattern same (defect or failure)	USPAT	2003/03/26 14:33
-	1486	((716/19) or (716/21)).CCLS.) ((716/2).CCLS.) ((716/4).CCLS.)	USPAT	2003/03/26 14:33
-	18	(inspect\$3 same pattern same (defect or failure)) and (((716/19) or (716/21)).CCLS.) ((716/2).CCLS.) ((716/4).CCLS.))	USPAT	2003/03/26 15:48
-	4233	wafer near3 inspection	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 17:16

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-	754	(wafer near3 inspection) and particle and pattern	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 17:17
-	24	(wafer near3 inspection) and particle and pattern and failure near3 probabilit\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/03/26 17:39